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JC860 U.S. PTO  
09/27/00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of )  
ANATOLY FABRIKANT ET AL. )  
For: IMPROVED SYSTEM FOR )  
SCATTEROMETRIC )  
MEASUREMENTS AND )  
APPLICATIONS )  
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San Francisco, California

JC564 U.S. PTO  
09/671715  
09/27/00

Patent Application  
Assistant Commissioner for Patents  
Washington, D.C. 20231

By Express Mail No: EL492667862US  
Dated: September 27, 2000

PATENT APPLICATION TRANSMITTAL

Sir:

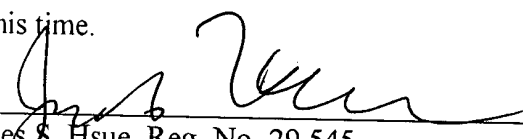
Transmitted herewith for filing is the patent application of inventors ANATOLY FABRIKANT, GUOHENG ZHAO, DANIEL C. WACK and MEHRDAD NIKOONAHAD, for "IMPROVED SYSTEM FOR SCATTEROMETRIC MEASUREMENTS AND APPLICATIONS."

Enclosed are:

1. Fifty (50) pages of the specification, including one-hundred fifteen (115) claims and an abstract.
2. Fourteen (14) sheets of drawings.

The filing fee will be deferred at this time.

Dated: September 27, 2000.

  
James S. Hsue, Reg. No. 29,545  
MAJESTIC, PARSONS, SIEBERT & HSUE P.C.  
Four Embarcadero Center, Suite 1100  
San Francisco, California 94111-4106  
Telephone: (415) 248-5500  
Facsimile: (415) 362-5418

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